

EAST Search History

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	34	((goodness near fit\$3) (curve near fitt\$3) (fitt\$3 near1 goodness) (foodness near2 measur\$4)) same ((control\$3 near limit\$1) (threshold near1 controL\$3) (control\$3 near threshold) (limit\$3 near value\$1))	US-PGPUB; USPAT; USOCR	OR	ON	2006/07/06 14:46
L2	1	((((goodness near fit\$3) (curve near fitt\$3) (fitt\$3 near1 goodness) (foodness near2 measur\$4)) with histor\$4) same ((control\$3 near limit\$1) (threshold near1 controL\$3) (control\$3 near threshold) (limit\$3 near value\$1))	US-PGPUB; USPAT; USOCR	OR	ON	2006/07/06 14:47
L3	1	(((((goodness near fit\$3) (curve near fitt\$3) (fitt\$3 near1 goodness) (foodness near2 measur\$4)) with histor\$4) same ((control\$3 near limit\$1) (threshold near1 controL\$3) (control\$3 near threshold) (limit\$3 near value\$1))) .clm.	US-PGPUB; USPAT; USOCR	OR	ON	2006/07/06 14:47
L4	1	("5574890").PN.	US-PGPUB; USPAT; USOCR	OR	OFF	2006/07/06 14:51
L5	2	(goodness near fit\$4) same ((resistance capacitance) with value\$1)	US-PGPUB; USPAT; USOCR	OR	OFF	2006/07/06 14:57
L6	0	(goodness near fit\$4) near ((resistance capacitance) with value\$1)	US-PGPUB; USPAT; USOCR	OR	OFF	2006/07/06 14:59
L7	0	("5,987,3981").PN.	US-PGPUB; USPAT; USOCR	OR	OFF	2006/07/06 15:00
L8	1	("5,987,398").PN.	US-PGPUB; USPAT; USOCR	OR	OFF	2006/07/06 15:08
L9	0	("k6,403,3891").PN.	US-PGPUB; USPAT; USOCR	OR	OFF	2006/07/06 15:08
L10	0	("6,403,3891").PN.	US-PGPUB; USPAT; USOCR	OR	OFF	2006/07/06 15:08
L11	1	("6,403,389").PN.	US-PGPUB; USPAT; USOCR	OR	OFF	2006/07/06 15:59
L13	1	(goodness near1 fit\$3) same ((usage us\$3) near (monitor\$3 and control\$3 and process\$3)) and structure\$1	US-PGPUB; USPAT; USOCR	OR	OFF	2006/07/06 15:49
L14	0	(curve near fitt\$3) with (screen\$3 near device\$1)	US-PGPUB; USPAT; USOCR	OR	OFF	2006/07/06 16:00
L15	77	(curve near fitt\$3) and (screen\$3 near device\$1)	US-PGPUB; USPAT; USOCR	OR	OFF	2006/07/06 16:00

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L16	400	(curve near fitt\$3) and ((screen\$3 near device\$1) (detect\$3 with defect\$1))	US-PGPUB; USPAT; USOCR	OR	OFF	2006/07/06 16:00
L17	5	(curve near fitt\$3) and ((screen\$3 near device\$1) and (detect\$3 with defect\$1))	US-PGPUB; USPAT; USOCR	OR	OFF	2006/07/06 16:01
L18	249	(curve near fitt\$3) and (process\$3 with (control\$3 monitor\$3)) and (detect\$3 with defect\$1)	US-PGPUB; USPAT; USOCR	OR	OFF	2006/07/06 16:03
L19	16	(curve near fitt\$3) and (process\$3 with (control\$3 monitor\$3)) and (detect\$3 with defect\$1) and (goodness near fit\$4)	US-PGPUB; USPAT; USOCR	OR	OFF	2006/07/06 16:04
L20	44	(curve near fitt\$3) and (process\$3 with (control\$3 monitor\$3)) and (detect\$3 with defect\$1) and ((goodness near1 (fit\$4 measur\$3)) (coefficient\$1 near correlation\$1))	US-PGPUB; USPAT; USOCR	OR	OFF	2006/07/06 16:12
L21	1	(curve near fitt\$3) and (process\$3 with (control\$3 monitor\$3)) and (detect\$3 with defect\$1) and ((goodness near1 (fit\$4 measur\$3)) (coefficient\$1 near correlation\$1)) and (sheet\$1 near (resistance resistivity))	US-PGPUB; USPAT; USOCR	OR	OFF	2006/07/06 16:07
L22	0	(curve near fitt\$3) and (process\$3 with (control\$3 monitor\$3)) and (detect\$3 with defect\$1) and ((goodness near1 (fit\$4 measur\$3)) (coefficient\$1 near correlation\$1)) and (test\$3 with (structure\$1 wafer\$1)) and (model\$1 base\$1 with statistic\$3)	US-PGPUB; USPAT; USOCR	OR	OFF	2006/07/06 16:08
L26	1	("6403389").PN.	US-PGPUB; USPAT; USOCR	OR	OFF	2006/07/06 17:27
S1	583	(702/179).CCLS.	US-PGPUB; USPAT; USOCR	OR	OFF	2006/07/05 09:20
S2	7	S1 and (monitor\$3 with defect\$1)	US-PGPUB; USPAT; USOCR	OR	OFF	2006/07/05 10:34
S3	6	((("6,403,389") or ("5,627,101") or ("5,987,398") or ("5,883.437") or ("6,466,038") or ("5,514,974") or ("6,087,189") or ("5,552,718"))).PN.	US-PGPUB; USPAT; USOCR	OR	OFF	2006/07/05 10:34
S4	7	((("6,403,389") or ("5,627,101") or ("5,987,398") or ("5,883.437") or ("6,466,038") or ("5,514,974") or ("6,087,189") or ("5,552,718"))).PN.	US-PGPUB; USPAT; USOCR	OR	OFF	2006/07/05 10:42
S5	1	("20030139908").PN.	US-PGPUB; USPAT; USOCR	OR	OFF	2006/07/06 09:36

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S6	1029	(CHARTERED with SEMICONDUCTOR)	US-PGPUB; USPAT; USOCR	OR	OFF	2006/07/05 11:14
S7	0	S6 and (lim near sheldon)	US-PGPUB; USPAT; USOCR	OR	OFF	2006/07/05 11:14
S8	13	(sheldon with lim)	US-PGPUB; USPAT; USOCR	OR	OFF	2006/07/05 11:14
S9	1	S8 and ((monitor\$3 near defect\$1) (goodness near (curve\$1 fit\$3)))	US-PGPUB; USPAT; USOCR	OR	ON	2006/07/05 11:15
S10	2	S6 and ((monitor\$3 near defect\$1) (goodness near (curve\$1 fit\$3)))	US-PGPUB; USPAT; USOCR	OR	ON	2006/07/05 11:17
S11	2339	((monitor\$3 near defect\$1) (goodness near (curve\$1 fit\$3))) not (S8 S6)	US-PGPUB; USPAT; USOCR	OR	ON	2006/07/05 11:17
S12	2339	((monitor\$3 near defect\$1) (goodness near (curve\$1 fit\$3))) not S8 not S6	US-PGPUB; USPAT; USOCR	OR	ON	2006/07/05 11:17
S13	2341	((monitor\$3 near defect\$1) (goodness near (curve\$1 fit\$3))) not S8	US-PGPUB; USPAT; USOCR	OR	ON	2006/07/05 11:17
S14	2340	((monitor\$3 near defect\$1) (goodness near (curve\$1 fit\$3))) not S6	US-PGPUB; USPAT; USOCR	OR	ON	2006/07/05 11:27
S15	0	((monitor\$3 near defect\$1) and (goodness near (curve\$1 fit\$3))) not S8	US-PGPUB; USPAT; USOCR	OR	ON	2006/07/05 11:18
S16	0	((monitor\$3 near defect\$1) same (goodness near (curve\$1 fit\$3)))	US-PGPUB; USPAT; USOCR	OR	ON	2006/07/05 11:28
S17	1	((monitor\$3 near defect\$1) and (goodness near (curve\$1 fit\$3)))	US-PGPUB; USPAT; USOCR	OR	ON	2006/07/05 11:28
S18	161	(goodness near (curve\$1 fit\$3)) and (control\$3 adj process\$3)	US-PGPUB; USPAT; USOCR	OR	ON	2006/07/05 14:54
S19	452	(700/110).CCLS.	US-PGPUB; USPAT; USOCR	OR	OFF	2006/07/05 11:33
S20	341	(700/109).CCLS.	US-PGPUB; USPAT; USOCR	OR	OFF	2006/07/05 11:33
S21	0	S18 and S19	US-PGPUB; USPAT; USOCR	OR	OFF	2006/07/05 11:33
S22	0	S18 and S20	US-PGPUB; USPAT; USOCR	OR	OFF	2006/07/05 11:33

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S23	2	S18 and S1	US-PGPUB; USPAT; USOCR	OR	OFF	2006/07/05 14:57
S25	0	(10/164091).CCLS.	US-PGPUB; USPAT; USOCR	OR	OFF	2006/07/05 11:47
S26	1	"10164091"	US-PGPUB; USPAT; USOCR	OR	OFF	2006/07/05 13:43
S27	1	("6665577").PN.	US-PGPUB; USPAT; USOCR	OR	OFF	2006/07/05 13:43
S28	1	S27 and calculat\$3 and (goodness near fit\$3)	US-PGPUB; USPAT; USOCR	OR	OFF	2006/07/05 13:43
S29	441	(goodness near (curve\$1 fit\$3)) same calculat\$3	US-PGPUB; USPAT; USOCR	OR	ON	2006/07/05 14:23
S30	18	(goodness near (curve\$1 fit\$3)) same calculat\$3 same monitor\$3	US-PGPUB; USPAT; USOCR	OR	ON	2006/07/05 14:23
S31	2	(goodness near (curve\$1 fit\$3)) same calculat\$3 same monitor\$3 same regression\$1	US-PGPUB; USPAT; USOCR	OR	ON	2006/07/05 14:24
S32	56	(goodness near (curve\$1 fit\$3)) same calculat\$3 same regression\$1	US-PGPUB; USPAT; USOCR	OR	ON	2006/07/05 14:32
S33	20	calculat\$3 with (goodness near fit\$3 near value\$1)	US-PGPUB; USPAT; USOCR	OR	ON	2006/07/05 14:34
S34	5	(calculat\$3 with (goodness near fit\$3 near value\$1)) and (curve\$1 near fit\$4)	US-PGPUB; USPAT; USOCR	OR	ON	2006/07/05 14:33
S35	36	("4475122" "4567610" "4736109" "4823393" "4945914" "5063603" "5189292" "5241166" "5245165" "5260556" "5363212" "5475468" "5506936" "5515451" "5572596").PN. OR ("5845008").URPN.	US-PGPUB; USPAT; USOCR	OR	OFF	2006/07/05 14:41
S36	96	monitor\$3 with (process\$3 near stability)	US-PGPUB; USPAT; USOCR	OR	ON	2006/07/05 14:48
S37	0	(monitor\$3 with (process\$3 near stability)) same (curve\$1 near fit\$4)	US-PGPUB; USPAT; USOCR	OR	ON	2006/07/05 14:42
S38	1	(monitor\$3 with (process\$3 near stability)) and (goodness near fit\$4)	US-PGPUB; USPAT; USOCR	OR	ON	2006/07/05 14:42
S39	1	(monitor\$3 with (process\$3 near stability)) and (fit\$3 with curve\$1)	US-PGPUB; USPAT; USOCR	OR	ON	2006/07/05 14:43

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S40	3	(monitor\$3 with (process\$3 near stability)) and (fit\$3 with value\$1)	US-PGPUB; USPAT; USOCR	OR	ON	2006/07/05 14:46
S41	1	(monitor\$3 with (process\$3 near stability)) and (fit\$3 with value\$1) and (linear with regression\$1)	US-PGPUB; USPAT; USOCR	OR	ON	2006/07/05 14:43
S42	0	(monitor\$3 with (process\$3 near stability)) and (coefficient near relat\$3)	US-PGPUB; USPAT; USOCR	OR	ON	2006/07/05 14:47
S43	0	(goodness near1 fit with regress\$4) near calculat\$3	US-PGPUB; USPAT; USOCR	OR	ON	2006/07/05 14:48
S44	21	(goodness near1 fit with regress\$4) same calculat\$3	US-PGPUB; USPAT; USOCR	OR	ON	2006/07/05 14:49
S45	12	(goodness near1 fit with regress\$4) and (degree near1 freedom)	US-PGPUB; USPAT; USOCR	OR	ON	2006/07/05 14:49
S46	8	(goodness near1 fit with regress\$4) and (degree near1 freedom) and (statistic\$3 with regress\$3)	US-PGPUB; USPAT; USOCR	OR	ON	2006/07/05 14:53
S47	19	(goodness near (curve\$1 fit\$3)) and (control\$3 adj process\$3) and (correlat\$3 with coefficient\$1)	US-PGPUB; USPAT; USOCR	OR	ON	2006/07/05 16:54
S48	328	(statistic\$3 near analys\$3) and (goodness near (curve\$1 fit\$4)) and (control\$3 monitor\$3 with device\$1)	US-PGPUB; USPAT; USOCR	OR	ON	2006/07/05 16:54
S49	23	((statistic\$3 near analys\$3) and (goodness near (curve\$1 fit\$4)))same (control\$3 monitor\$3 with device\$1)	US-PGPUB; USPAT; USOCR	OR	ON	2006/07/05 16:55
S50	0	((statistic\$3 near analys\$3) and (goodness near (curve\$1 fit\$4))) same (process\$3 adj control\$3)	US-PGPUB; USPAT; USOCR	OR	ON	2006/07/05 16:55
S51	0	((statistic\$3 near analys\$3) and (goodness near (curve\$1 fit\$4))) with (process\$3 adj control\$3)	US-PGPUB; USPAT; USOCR	OR	ON	2006/07/05 16:56
S52	9	(goodness near (curve\$1 fit\$4)) same (process\$3 adj control\$3)	US-PGPUB; USPAT; USOCR	OR	ON	2006/07/05 17:02
S53	1	(semiconductor\$1 near device\$1) same (goodness near (fit\$3 measur\$5))	US-PGPUB; USPAT; USOCR	OR	ON	2006/07/05 17:02
S54	21	((fit\$3 near measurement\$1) with (usage\$1 us\$3)) same device\$1	US-PGPUB; USPAT; USOCR	OR	OFF	2006/07/06 09:22
S55	2	(measur\$3 near device\$1) same (goodness near (fit\$3 measurement\$1 measur\$4 control\$3))	US-PGPUB; USPAT; USOCR	OR	OFF	2006/07/06 09:22
S56	1	(goodness near1 fit\$3) same ((usage us\$3) near (monitor\$3 and control\$3 and process\$3))	US-PGPUB; USPAT; USOCR	OR	OFF	2006/07/06 15:48

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S57	11	(goodness adj fit\$1) and ((independent near variable\$1) with device\$1)	US-PGPUB; USPAT; USOCR	OR	OFF	2006/07/06 09:27
S58	43	model\$1base\$1 near monitor\$3	US-PGPUB; USPAT; USOCR	OR	OFF	2006/07/06 09:45
S59	0	(model\$1base\$1 near monitor\$3) and (goodness near1 fit\$1)	US-PGPUB; USPAT; USOCR	OR	OFF	2006/07/06 09:37
S60	0	(model\$1base\$1 near monitor\$3) and (goodness with curve\$1)	US-PGPUB; USPAT; USOCR	OR	OFF	2006/07/06 09:37
S61	0	(model\$1base\$1 near monitor\$3) and (coeffecient\$1 with correlat\$3)	US-PGPUB; USPAT; USOCR	OR	OFF	2006/07/06 09:37
S62	4	((manipulat\$3 calculat\$3 form\$3) with (goodness near1 (fit\$3 measur\$4 statistical\$3))) and ((semiconductor\$1 wafer\$1) with (form\$3 near process\$3))	US-PGPUB; USPAT; USOCR	OR	ON	2006/07/06 14:44